## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT

Satoru HANZAWA et al.

SERIAL NO.

(Con. of 10/201,317)

FILING DATE

25 June 2003

**FOR** 

SEMICONDUCTOR DEVICE

**GROUP ART UNIT:** 

2818 (Anticipated)

EXAMINER

Viet Q. Nguyen (Anticipated)

COMMISSIONER FOR PATENTS

P. O. Box 1450

Alexandria, Virginia 22313-1450

# INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97 & § 1.98

SIR:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

Since all the references were already considered in parent application Serial No. 10/201,317, no copies of the references are required.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

Date: 25 June 2003

David J. Zibellí (Reg. No. 36,394)

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## Sheet 1 of 1

	TION DISCLOS		Atty Docket No Serial No. Inventors Filed Group Art Unit Examiner		: 2928 : : HAN : 25 J : 2818 : Viet	IZAW une 2 3	A, et al. 2003
		U.S. PAT	ENT DOCUMEN	NTS			
Examiner <u>Initial</u>	Patent <u>Number</u>	Patent <u>Date</u>	<u>Name</u>		Class Subcl		iling Date
	6,452,858 6,545,897 6,545,525 2001/0028581 2001/0009519 2001/0001598 6,535,435 6,501,672 6,480,425 6,452,858	09-2002 04-2003 04-2003 10-2001 07-2001 05-2001 03-2003 12-2002 11-2002 09-2002	HANZAWA, e FUJISAWA, e ITOH, et al YANAGISAWA FUJISAWA et NARUI, et al. TANAKA, et a SEKIGUCHI, e YANAGISAWA HANZAWA, e	t al. A, et al. I. et al. A, et al. t al.	365/5 365/1 365/1 365/7 al365/1 365/2	30.08 24  89.09 51 49 89.09 2	5 0 5
Examiner Initial	Document <u>Number</u>	<u>Date</u>	Country	Clas Sub	ss/ class		nslation <u>No</u>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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# INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449

ATTY. DOCKET NO. 29287/137	SERIAL NO. (Con of 10/201,317)			
APPLICANT HANZAWA et al.				
FILING DATE Viet D. Nguyen (Anticipated)	GROUP 2918 (Anticipated)			

## U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
	2002/0041531 A1	04/11/02	TANAKA et al.	365	205	

#### FOREIGN PATENT DOCUMENTS

				-		TRANSLATION	
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	YES	NO
	JP 02001195879A	07/01	Japan				
	JP 407057461 A	03/95	Japan				
				4			
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## OTHER DOCUMENTS

EXAMINER INITIAL	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
-	IEEE International Solid-State Circuits Conference, Digest of Technical Papers, 1972, pp. 10-11.*
	IEE Electronics Letters, May 13, 1999, Vol. 35, No. 10, pp. 848-850.*
	European Solid-State Circuits Conference, Digest of Technical Papers, 1992, pp. 131-134.*
	IEEE Journal of Solid-State Circuits, May 2000, Vol. 35, No. 5, pp. 691-695.

<sup>\*</sup>Mentioned in the Specification

	EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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